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| SERIAL NUMBER 10/774,588 | FILING DATE 02/10/2004 RULE | CLASS 438 | GROUP ART UNIT 2891 | ATTORNEY DOCKET NO. 501.37465C10 |
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APPLICANTS

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** CONTINUING DATA *yes* *✓* *****
 This application is a CON of 10/424,105 04/28/2003 PAT 6,855,642
 which is a CON of 09/939,600 08/28/2001 PAT 6,596,650
 which is a CON of 09/494,036 01/31/2000 PAT 6,518,201
 which is a CON of 09/380,646 09/07/1999 PAT 6,239,041
 which is a 371 of PCT/JP98/00892 03/04/1998

** FOREIGN APPLICATIONS *yes* *✓* *****
 JAPAN 9-50781 03/05/1997

IF REQUIRED, FOREIGN FILING LICENSE GRANTED
 ** 05/07/2004

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|---|------------------------------|-------------------------|----------------------|----------------------------|
| Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no | STATE OR COUNTRY JAPAN | SHEETS DRAWING 21 | TOTAL CLAIMS 8 | INDEPENDENT CLAIMS 1 |
|---|------------------------------|-------------------------|----------------------|----------------------------|

35 USC 119 (a-d) conditions met
☒ yes ☐ no ☐ Met after
allowance

Verified and Acknowledged
 Examiner's Signature *V. J. [Signature]* Initials *VJ*

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TITLE
 Method for fabricating semiconductor integrated circuit device

☐ All Fees